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PATENT Customer No. 22,852 Attorney Docket No. 3180.0285

#### IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:	)
KUNIHIRO MITSUTAKE ET AL.	)
Serial No.: 09/931,916	) Group Art Unit: 2857
Filed: August 20, 2001	) ) Examiner: M. Baran )
For: METHOD, APPARATUS, AND COMPUTER PROGRAM OF SEARCHING FOR CLUSTERING FAULTS IN SEMICONDUCTOR DEVICE MANUFACTURING	, ) ) ) )

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

### **INFORMATION DISCLOSURE STATEMENT UNDER 37 C.F.R. § 1.97(b)**

Pursuant to 37 C.F.R. §§ 1.56 and 1.97(b), applicants bring to the attention of the Examiner the document listed on the attached PTO 1449. This Information Disclosure Statement is being filed concurrently with a Request for Continued Examination for the above-referenced application.

A copy of the listed document is attached.

Applicants respectfully request that the Examiner consider the listed document and indicate that it was considered by making an appropriate notation on the attached form.

In lieu of a statement of relevance or translation of the non-English document, a

Notification of the First Office Action issued by the Patent Office of the People's

Republic of China in a corresponding Chinese application citing the document and

setting forth the relevance thereof is enclosed. In addition, an English-language translation of the Notification and English-language abstract of the document are provided.

This submission does not represent that a search has been made or that no better art exists and does not constitute an admission that the listed document is material or constitutes "prior art." If the Examiner applies the document as prior art against any claim in the application and applicants determine that the cited document does not constitute "prior art" under United States law, applicants reserve the right to present to the office the relevant facts and law regarding the appropriate status of such document.

Applicants further reserve the right to take appropriate action to establish the patentability of the disclosed invention over the listed document, should the document be applied against the claims of the present application.

If there is any fee due in connection with the filing of this Statement, please charge the fee to our Deposit Account No. 06-0916.

Respectfully submitted,

FINNEGAN, HENDERSON, FARABOW, GARRETT & DUNNER, L.L.P.

Dated:

By:

Pichard V-Pure

Reg. No. 31.744

INFORMATION DISCLOSURE CITATION

Atty. Docket No.	3180.0285	8	Appln. No.	09/931,916	
Applicant	Mitsutake et al. 🛱	AU6 1 2 2004 2			
Filing Date	August 20, 2001	es di	Group:	2857	
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U.S. PATENT DOCUMENTS						
Examiner Initial*	Document Number	Issue Date	Name	Class	Sub Class	Filing Date If Appropriate
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FOREIGN PATENT DOCUMENTS						
	Document Number	Publication Date	Country	Class	Sub Class	Translation Yes or No
	1207531	2/10/99	China			Abstract
					-	

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)				

Examiner Date Consi		Date Considered		
*Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.				
Form PTO 1449		Patent and Trademark Office - U.S. Department of Commerce		



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Filed: August 20, 2001	) Examiner: M. Baran
For: METHOD, APPARATUS, AND COMPUTER PROGRAM OF SEARCHING FOR CLUSTERING FAULTS IN SEMICONDUCTOR DEVICE MANUFACTURING	) ) ) )

#### **Mail Stop AF**

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

#### **REQUEST FOR INITIALED FORM PTO 1449**

An Information Disclosure Statement was filed in this application on August 20, 2001. In reviewing our file, we find that we have not received from your Office a copy of the Form PTO-1449 which would serve as acknowledgment of receipt of the Information Disclosure Statement and as an indication that the references were considered by the examiner.

Copies of the Information Disclosure Statement, the Information Disclosure Citation on Form PTO-1449, and the postcard that was filed with the Information Disclosure Statement and was stamped by the U.S. Patent and Trademark Office to indicate receipt of the papers, are attached.

The Examiner is respectfully requested either to send us a duplicate of the copy of the Form PTO-1449 or issue a Supplemental Notice of Allowability (PTOL-37) which both acknowledges receipt of the Information Disclosure Statement and the Information Disclosure Citation, and indicates that the references were considered by the Examiner.

If there are any fees due in connection with the filing of this Request, please charge the fees to Deposit Account No. 06-0916.

Respectfully submitted,

FINNEGAN, HENDERSON, FARABOW, GARRETT & DUNNER, L.L.P.

Dated:

Richard V. Burgujian

Reg. Nb. 31.744



Attorney Docket No.:03180.0285 Customer Number: 22,852

### IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:	)
Kunihiro MITSUTAKE et al.	)
Serial No.:Not yet assigned	) Group Art Unit: Not assigned
Filed: August 20, 2001	) Examiner: Not assigned

For: METHOD, APPARATUS, AND COMPUTER PROGRAM OF SEARCHING FOR CLUSTERING FAULTS IN SEMICONDUCTOR DEVICE MANUFACTURING

Assistant Commissioner for Patents Washington, DC 20231

Sir:

### INFORMATION DISCLOSURE STATEMENT UNDER 37 C.F.R. § 1.97(b)

Pursuant to 37 C.F.R. §§ 1.56 and 1.97(b), applicants bring to the Examiner's attention the document listed on attached Form PTO-1449. A copy of the listed document is attached. Applicants respectfully request that the Examiner consider the document listed on attached Form PTO-1449 and indicate that it was considered by making an appropriate notation on this form.

This Information Disclosure Statement is being filed with the abovereferenced application.

This submission does not represent that a search has been made or that no better art exists and does not constitute an admission that the listed document is material or constitutes "prior art." If the Examiner applies the document as prior art against any claim in the application and applicants determine that the cited document does not constitute "prior art" under United States law, applicants

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202-408-408-

Attorney Docket No.:03180.0285 Customer Number: 22,852

reserve the right to present to the office the relevant facts and law regarding the appropriate status of such document.

Applicants further reserve the right to take appropriate action to establish the patentability of the disclosed invention over the listed document, should the document be applied against the claims of the present application.

If there is any fee due in connection with the filing of this Statement, please charge the fee to our Deposit Account No. 06-0916.

Respectfully submitted.

FINNEGAN, HENDERSON, FARABOW, GARRETT & DUNNER, L.L.P.

By:

Richard V. Burgujian

Reg. No. 31,744

Dated: August 20, 2001

Enclosures RVB/FPD/dvz

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HINGTON, OC. 20005



## INFORMATION DISCLOSURE CITATION (Use several sheets if necessary)

Atty. Docket No	. 03180.0285	Serial No.	Not Yet Assigned				
Applicant	Kunihiro MITSUTAKE et	al.					
Filing Date	August 20, 2001		Group				
	U	S. PATENT	DOCUMENTS				
Examiner Initial*	Document Number	Date	Name	Class	Sub Class	Filing Date If Appropriate	
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	FOR	EIGN PATEN	TDOCUMENTS				
	Document Number	Date	Country	Class	Sub Class	Translation Yes or No	
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	OTHER DOCUMENTS (Inc						
	IKOTA, M. et al., "Discrim 1997 Second Int. Worksh	ination of Clus op Statistical I	stered Defects on Wat Metrology, pp. 52-55.	ers Using	Statistica	l Methods", Proc.	
Examiner			Date Considered				
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